MOS FET

SK8603190L

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### Silicon N-channel MOS FET

For Load-switching / For DC-DC Converter

#### ■ Features

- Low Drain-source On-state Resistance : RDS(on) typ = 10 m $\Omega$  (VGS = 4.5 V)
- Halogen-free / RoHS compliant (EU RoHS / UL-94 V-0 / MSL : Level 1 compliant)

■ Marking Symbol : 19

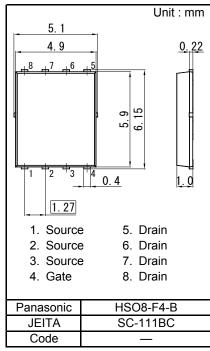
#### ■ Packaging

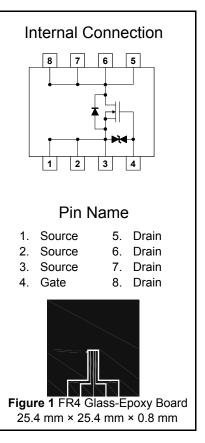
Embossed type (Thermo-compression sealing): 3 000 pcs / reel (standard)

■ Absolute Maximum Ratings Ta = 25 °C

Parameter			Symbol	Rating		Unit		
Drain to Source Voltage			VDS	30		V		
Gate to Source Voltage			VGS	±20				
Drain Current	Ta = 25 °C, t = 10 s *1			16				
	Ta = 25 °C, DC *1		ID	12	Α			
	Tc = 25 °C			19				
	Pulsed	d, Tch < 150 °C <sup>*2</sup>	1	48				
Total Power Dissipation		Ta = 25 °C, DC *1	PD	2.7	W			
		Tc = 25 °C	FD	19				
Thermal Resistance		Channel to Ambient	Rth(ch-a)	45		°C / W		
Hiemiai Nesisi	ance	Channel to Case	Rth(ch-c)	6.6		-0/00		
Channel Temperature			Tch	150				
Operating ambient temperature			Topr	-40 to	+85	°C		
Storage Temperature Range			Tstg	-55 to	+150			
Avalanche Current (Single pulse) *3			IAR	8		Α		
Avalanche Energy (Single pulse) *3			EAR	8		mJ		

- Note \*1 Device mounted on a glass-epoxy board in Figure 1
  - \*2 Pulse test: Ensure that the channel temperature does not exceed 150 °C
  - \*3 VDD = 24 V, VGS = 10 to 0 V, L = 0.1 mH, Tch = 25  $^{\circ}$ C (initial)





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#### ■ Electrical Characteristics Ta = 25 °C ± 3 °C

#### Static Characteristics

Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Drain-source Breakdown Voltage	VDSS	ID = 1 mA, VGS = 0 V	30			V
Zero Gate Voltage Drain Current	IDSS	VDS = 30 V, VGS = 0 V			10	μΑ
Gate-source Leakage Current	IGSS	VGS = $\pm 16$ V, VDS = 0 V			±10	μΑ
Gate-source Threshold Voltage		ID = 1.01 mA, VDS = 10 V	1		3	V
Drain-source On-state Resistance	RDS(on)1	ID = 8 A, VGS = 10 V		7	10	mΩ
Diani-source On-sidle Nesistance	RDS(on)2	ID = 8 A, VGS = 4.5 V		10	14	

#### **Dynamic Characteristics**

Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Input Capacitance	Ciss		1,,,,,,	780	1 092	<u> </u>
Output Capacitance	Coss	VDS = 10 V, VGS = 0 V		160	224	pF
Reverse Transfer Capacitance	Crss	f = 1 MHz		61	98	
Turn-on Delay Time *1	td(on)	VDD = 15 V, VGS = 0 to 10 V ID = 8 A		7		ns
Rise Time *1	tr			3		
Turn-off Delay Time *1	td(off)	VDD = 15 V, VGS = 10 to 0 V		34		no
Fall Time *1	tf	ID = 8 A		4		ns
Total Gate Charge	Qg	VDD = 15 V VCC = 0 to 4 5 V		6.3		
Gate to Source Charge	Qgs	VDD = 15 V, VGS = 0 to 4.5 V ID = 8 A		2.5		nC
Gate to Drain Charge	Qgd	ID - 0 A		2.1		
Gate resistance	rg	f = 5 MHz		1.2	3	Ω

### **Body Diode Characteristic**

Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Diode Forward Voltage	VSD	IS = 8 A, VGS = 0 V		8.0	1.2	V

Note: 1. Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 Measuring methods for transistors.

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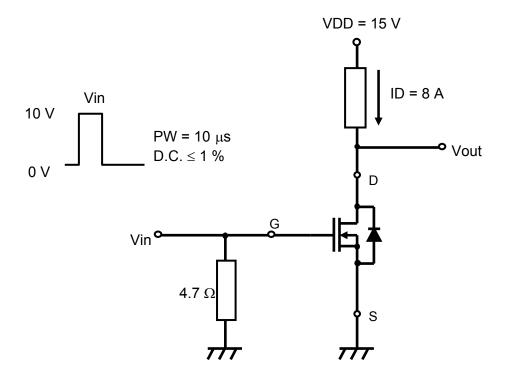
<sup>2. \*1</sup> Measurement circuit for Turn-on Delay Time / Rise Time / Turn-off Delay Time / Fall Time

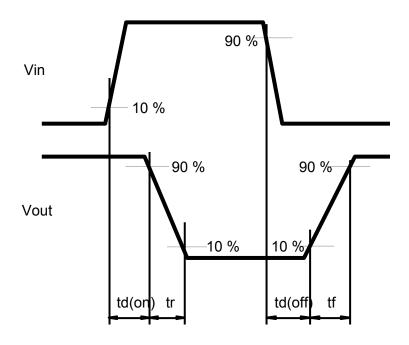
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\*1 Measurement circuit for Turn-on Delay Time / Rise Time / Turn-off Delay Time / Fall Time



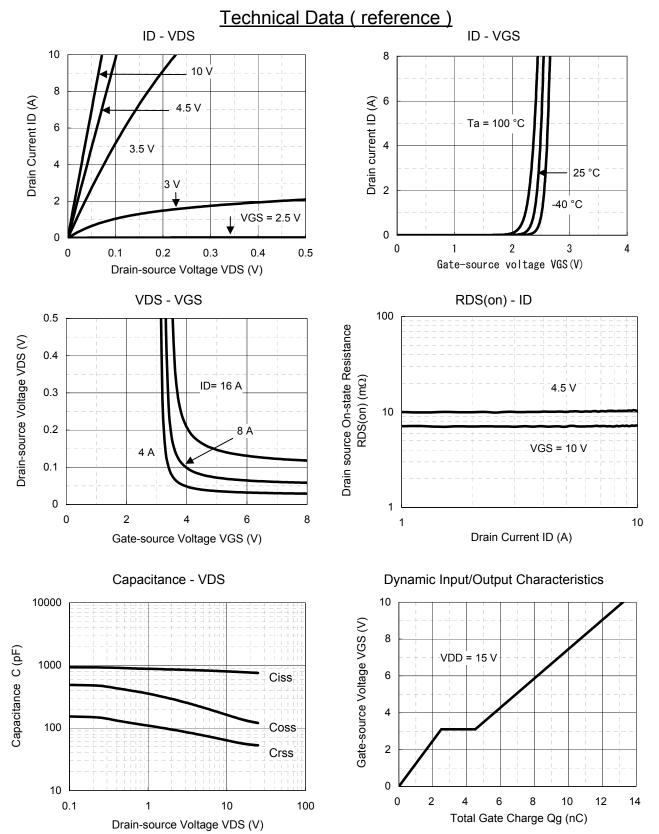


Established: 2012-09-14 Revised: 2013-05-31

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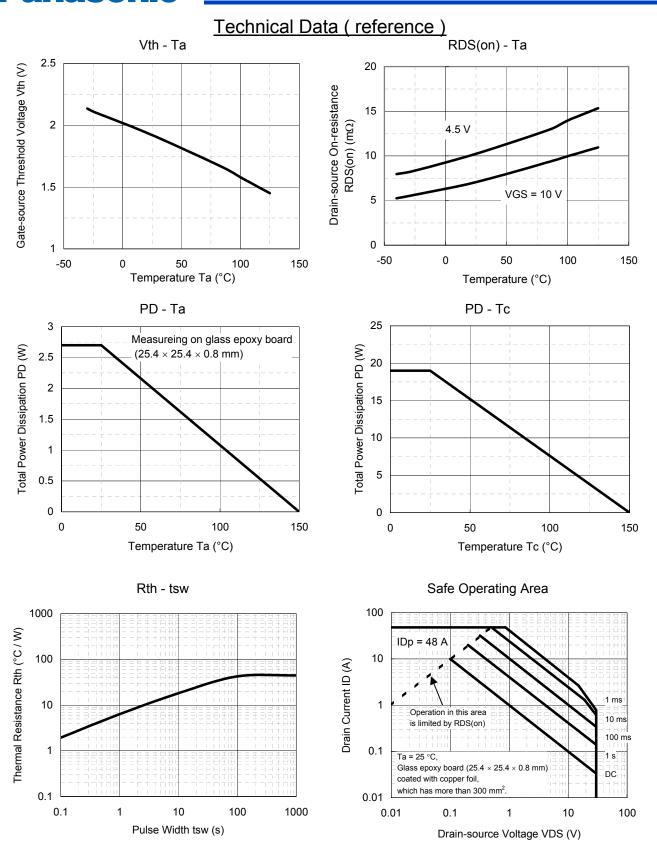
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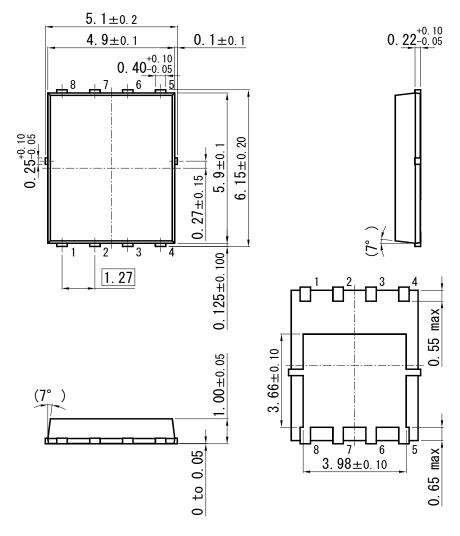
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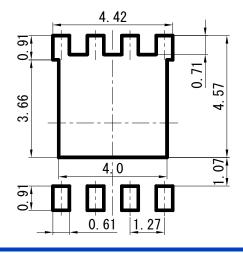
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## HSO8-F4-B



■ Land Pattern (Reference) (Unit : mm)



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